PATENT NUMBER and ISSUE DATE

UTILITY Patent Application

APPL NUM : FILING DATE CI	LASS SUI	BCLASS	GAU 2012	الملا	EXAMINER	
**APPLICANTS: Baek Kyou	ing-Yoon, I	Bae Young	-Guk;		5 kve	P
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**CONTINUING DATA VERIFIED:						
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** FOREIGN APPLICATIONS VERIFIED: REPUBLIC OF KOREA 2001-12005 03/08/2001						
PG-PUB DO NOT PUBLISH		RESCI				
Foreign priority claimed	u yes u			ATTORN	EY DOCKET	NO
35 USC 119 conditions met □ yes □ no Verified and Acknowledged Examiners's initials SEC.912						
TITLE: Overlay key, method of manufacturing the same and method of measuring an overlay degree using the same						
				U.S.DEPT. O	COMMITALS IN	C SOL(Rev 12-9
			084877			

NOTICE OF ALLOWANCE MAILED	Assistant Examiner	Total Claims Print Claim for O.G.
Amount Due Date Paid	Primary Examiner PREPARED FOR ISSUE	Sheeb Drwp Figs.Drwp Print Fig.
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